

<b>Notice of References Cited</b>	Application/Control No. 10/614,415	Applicant(s)/Patent Under Reexamination JONG ET AL.	
	Examiner Chuck Huynh	Art Unit 2683	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2004/0204134	10-2004	Khazaka et al.	455/566
	B	US-2003/0126560	07-2003	Kurapati et al.	715/514
	C	US-2004/0139208	07-2004	Tuli, Raja	709/230
	D	US-5,895,471	04-1999	King et al.	707/104.1
	E	US-6,032,182	02-2000	Mullen-Schultz, Gary Lee	709/223
	F	US-6,272,484	08-2001	Martin et al.	707/1
	G	US-6,009,442	12-1999	Chen et al.	715/522
	H	US-5,991,760	11-1999	Gauvin et al.	707/10
	I	US-2003/0084098	05-2003	Lavin et al.	709/203
	J	US-2005/0097458	05-2005	Wilson, Eric	715/517
	K	US-2004/0032340	02-2004	Lingafeldt et al.	340/870.02
	L	US-2002/0156832	10-2002	Duri et al.	709/203
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.